

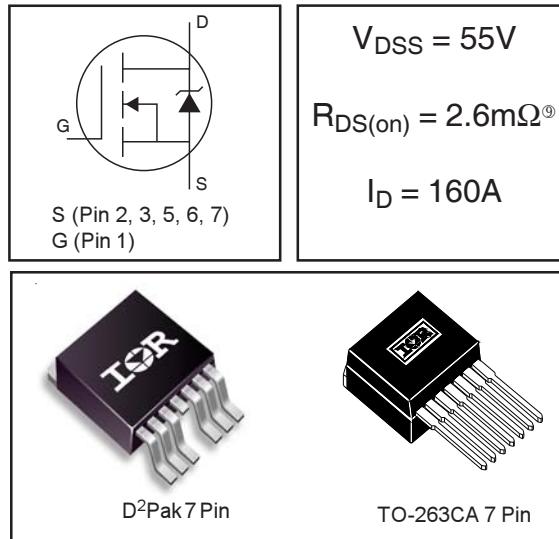
### Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

### Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

### HEXFET® Power MOSFET



### Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	240	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (See Fig. 9)	170	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	160	
I <sub>DM</sub>	Pulsed Drain Current ①	1000	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	440	mJ
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ③	680	
I <sub>AR</sub>	Avalanche Current ④	See Fig.12a,12b,15,16	A
E <sub>AR</sub>	Repetitive Avalanche Energy ⑤		mJ
T <sub>J</sub>	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

### Thermal Resistance

	Parameter	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case ⑥	—	0.50	°C/W
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50	—	
R <sub>θJA</sub>	Junction-to-Ambient ⑦	—	62	
R <sub>θJA</sub>	Junction-to-Ambient (PCB Mount, steady state) ⑧	—	40	

HEXFET® is a registered trademark of International Rectifier.

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

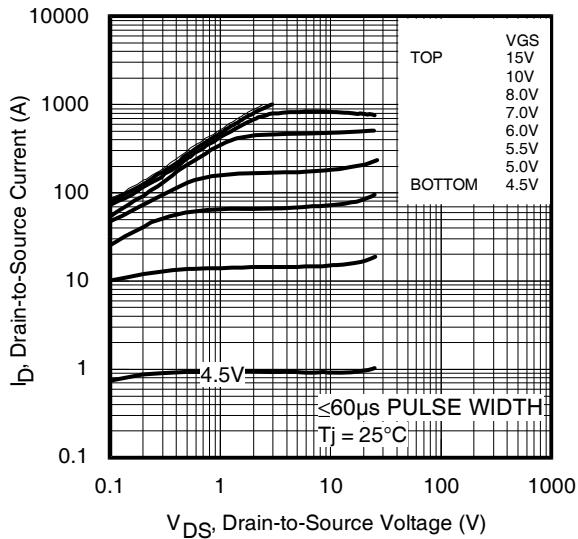
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.05	—	V/ $^{\circ}\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS}(\text{on}) \text{ SMD}}$	Static Drain-to-Source On-Resistance	—	2.0	2.6	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 140\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$
$g_{\text{fs}}$	Forward Transconductance	110	—	—	S	$V_{\text{DS}} = 25\text{V}, I_D = 140\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{\text{DS}} = 55\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 55\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{\text{GS}} = -20\text{V}$
$Q_g$	Total Gate Charge	—	130	200	nC	$I_D = 140\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	53	—		$V_{\text{DS}} = 44\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	49	—		$V_{\text{GS}} = 10\text{V}$ ③
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	23	—	ns	$V_{\text{DD}} = 28\text{V}$
$t_r$	Rise Time	—	130	—		$I_D = 140\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	80	—		$R_G = 2.4\Omega$
$t_f$	Fall Time	—	52	—		$V_{\text{GS}} = 10\text{V}$ ②
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{\text{iss}}$	Input Capacitance	—	7820	—	pF	$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	1260	—		$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	610	—		$f = 1.0\text{MHz}$ , See Fig. 5
$C_{\text{oss}}$	Output Capacitance	—	4310	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 1.0\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	980	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 44\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss eff.}}$	Effective Output Capacitance	—	1540	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V to } 44\text{V}$

**Diode Characteristics**

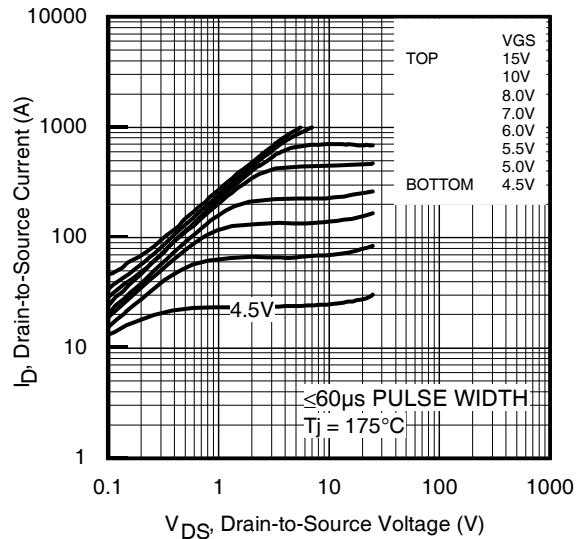
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	240	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	1000		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 140\text{A}, V_{\text{GS}} = 0\text{V}$ ③
$t_{rr}$	Reverse Recovery Time	—	45	68	ns	$T_J = 25^\circ\text{C}, I_F = 140\text{A}, V_{\text{DD}} = 28\text{V}$ $dI/dt = 100\text{A}/\mu\text{s}$ ③
$Q_{rr}$	Reverse Recovery Charge	—	35	53	nC	

**Notes:**

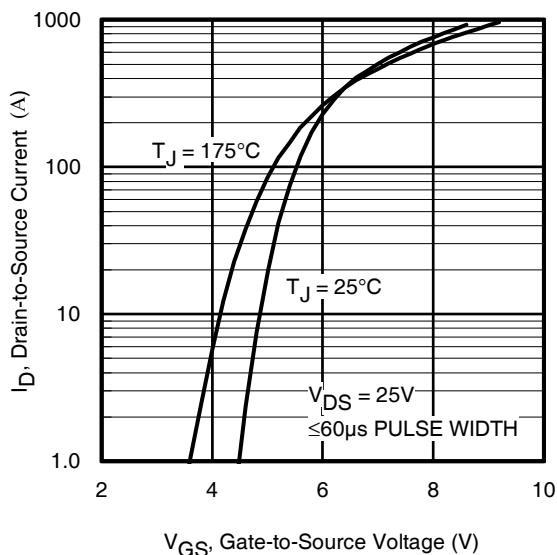
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L=0.043\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 140\text{A}$ ,  $V_{\text{GS}} = 10\text{V}$ . Part not recommended for use above this value.
- ③ Pulse width  $\leq 1.0\text{ms}$ ; duty cycle  $\leq 2\%$ .
- ④  $C_{\text{oss eff.}}$  is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 80%  $V_{\text{DSS}}$ .
- ⑤ Limited by  $T_{J\text{max}}$ , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population. 100% tested to this value in production.
- ⑦ This is applied to D<sup>2</sup>Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑧  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑨ Solder mounted on IMS substrate.



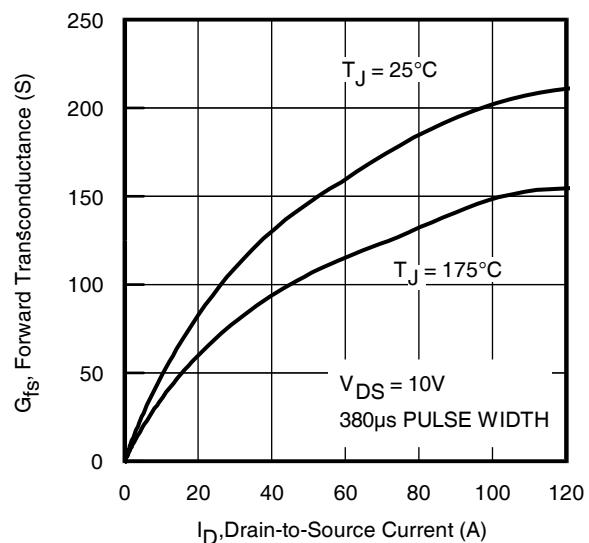
**Fig 1.** Typical Output Characteristics



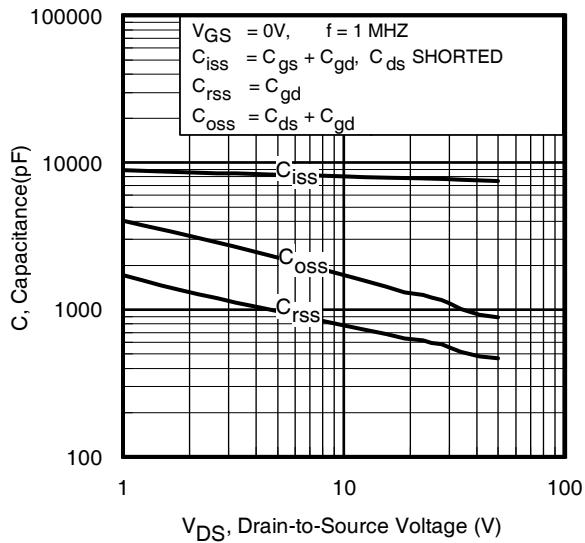
**Fig 2.** Typical Output Characteristics



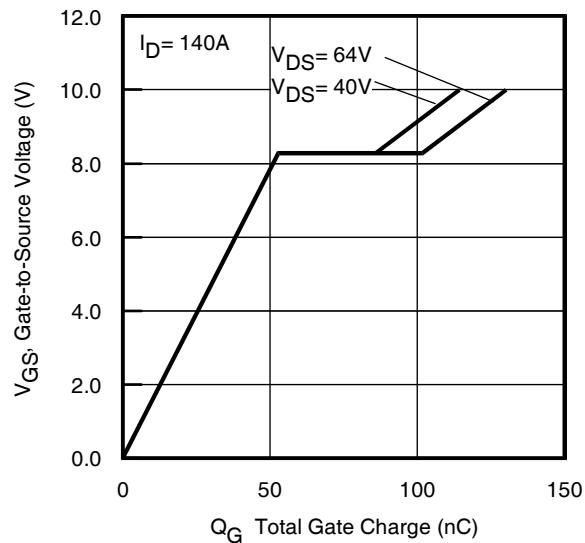
**Fig 3.** Typical Transfer Characteristics



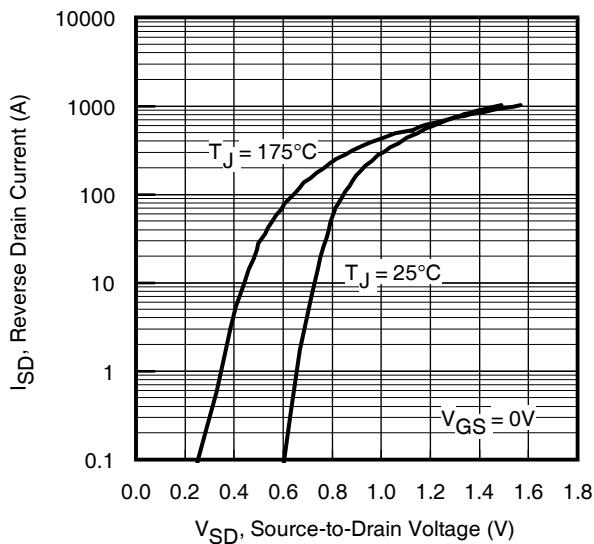
**Fig 4.** Typical Forward Transconductance vs. Drain Current



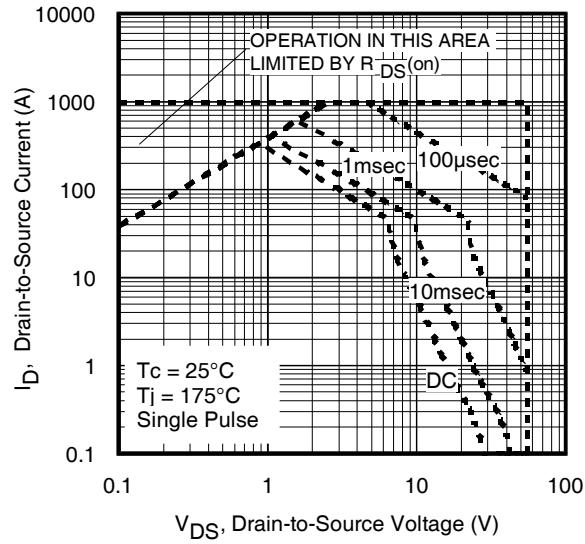
**Fig 5.** Typical Capacitance vs.  
Drain-to-Source Voltage



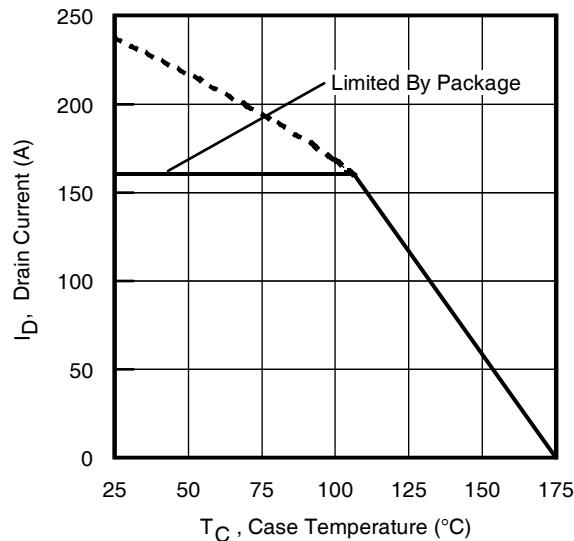
**Fig 6.** Typical Gate Charge vs.  
Gate-to-Source Voltage



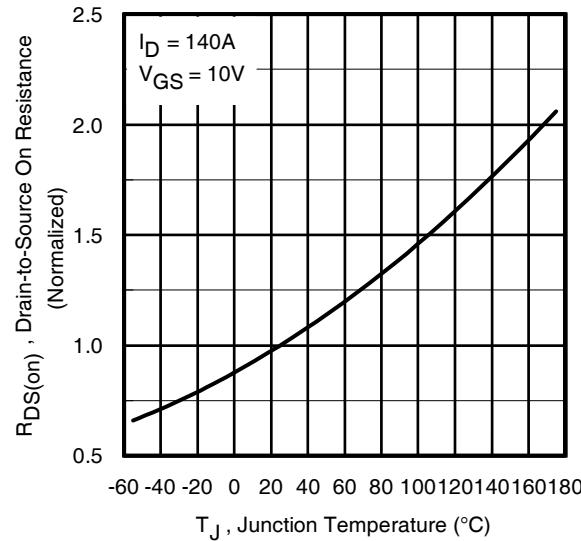
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



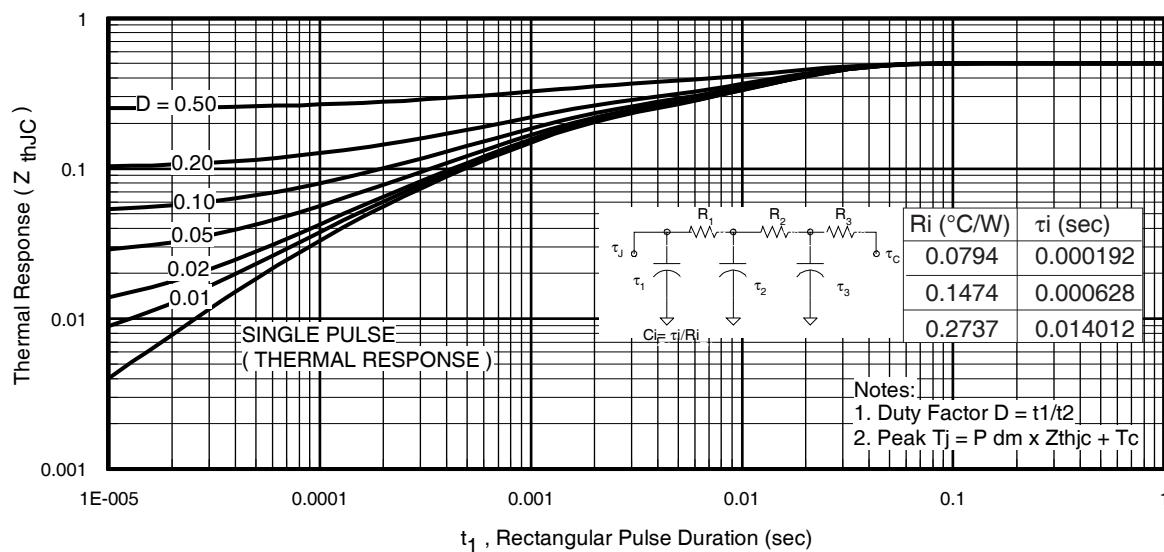
**Fig 8.** Maximum Safe Operating Area



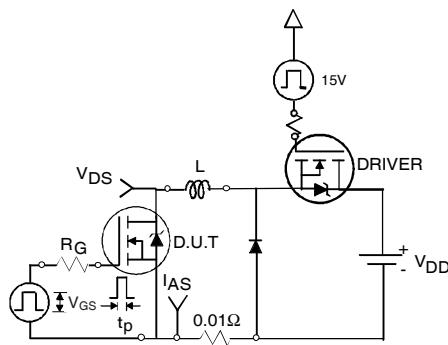
**Fig 9.** Maximum Drain Current vs.  
Case Temperature



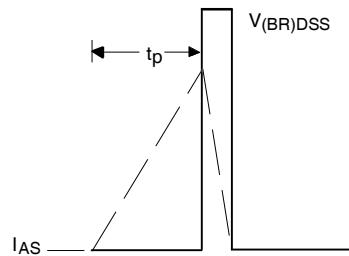
**Fig 10.** Normalized On-Resistance  
vs. Temperature



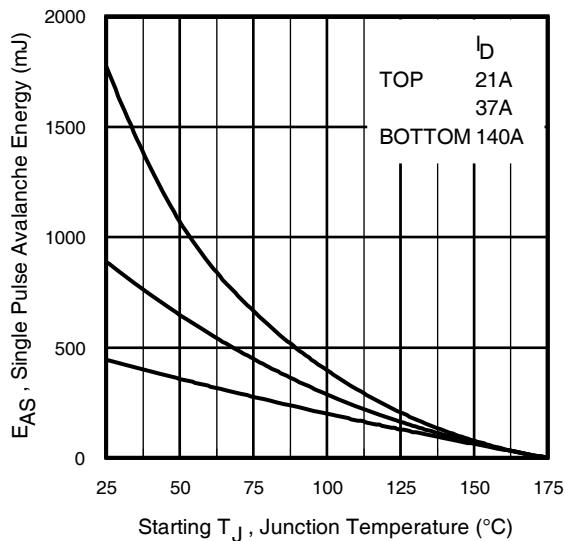
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



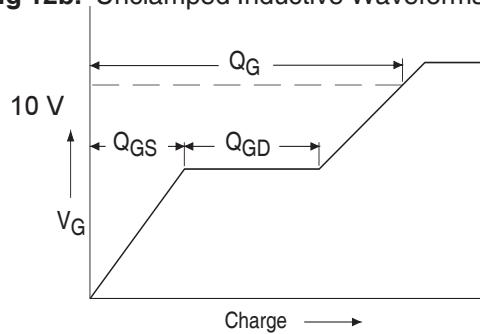
**Fig 12a.** Unclamped Inductive Test Circuit



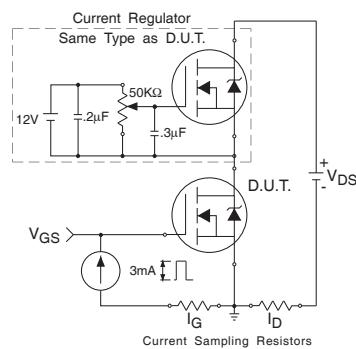
**Fig 12b.** Unclamped Inductive Waveforms



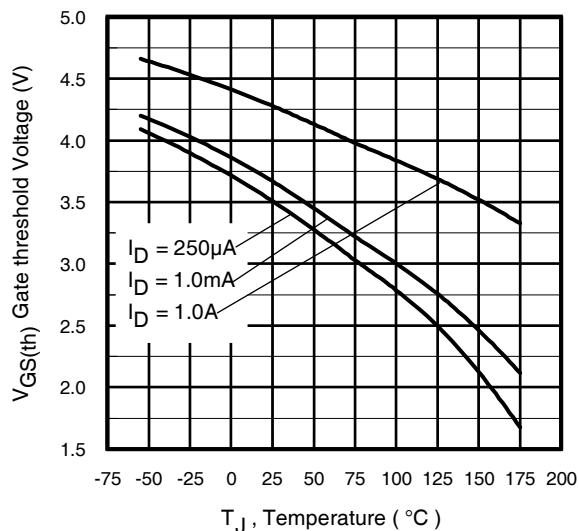
**Fig 12c.** Maximum Avalanche Energy vs. Drain Current



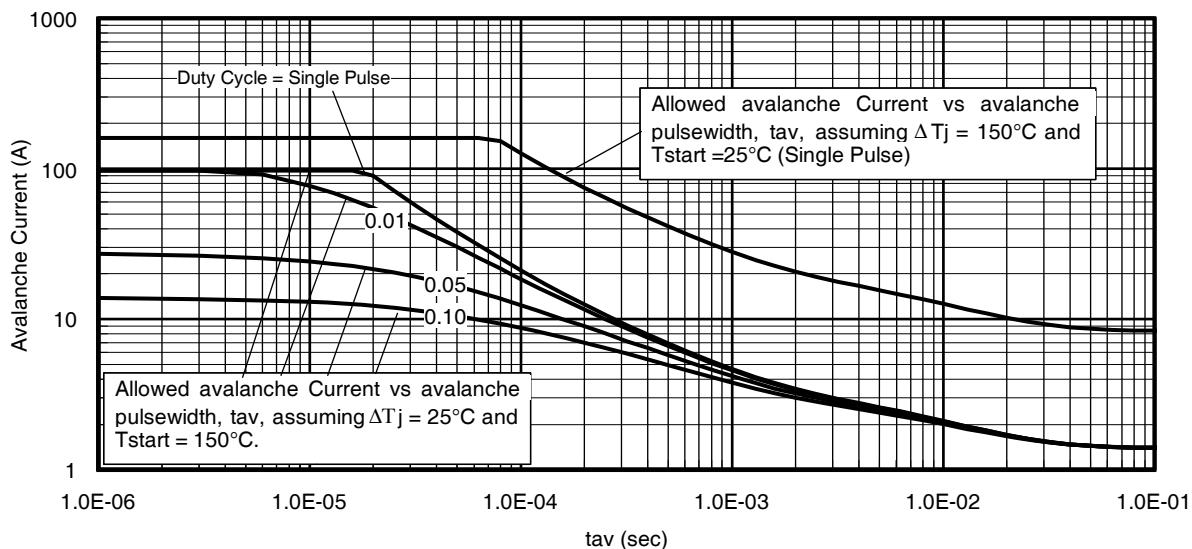
**Fig 13a.** Basic Gate Charge Waveform



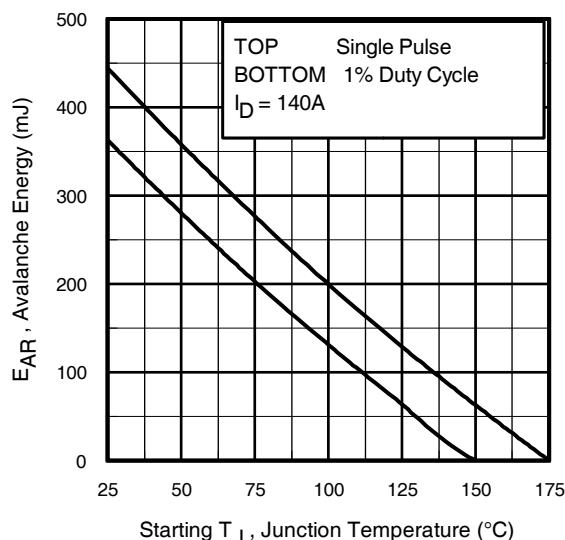
**Fig 13b.** Gate Charge Test Circuit



**Fig 14.** Threshold Voltage vs. Temperature



**Fig 15.** Typical Avalanche Current vs.Pulsewidth



**Fig 16.** Maximum Avalanche Energy  
vs. Temperature

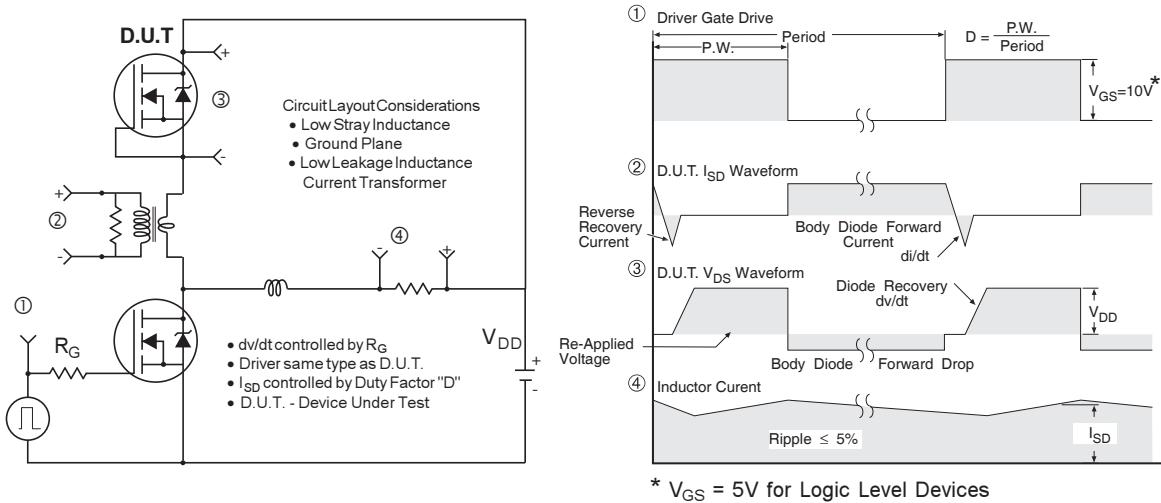
**Notes on Repetitive Avalanche Curves , Figures 15, 16:  
(For further info, see AN-1005 at [www.irf.com](http://www.irf.com))**

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I<sub>av</sub> = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 15, 16).
- t<sub>av</sub> = Average time in avalanche.
- D = Duty cycle in avalanche = t<sub>av</sub> · f
- Z<sub>thJC</sub>(D, t<sub>av</sub>) = Transient thermal resistance, see figure 11

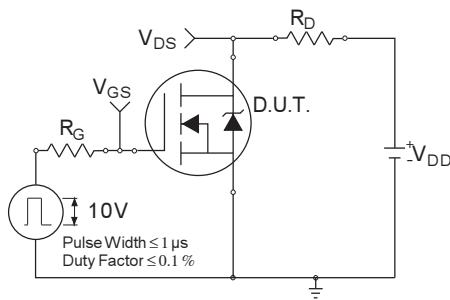
$$P_{D \text{ (ave)}} = 1/2 ( 1.3 \cdot BV \cdot I_{av} ) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

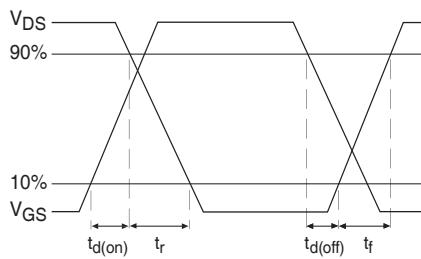
$$E_{AS \text{ (AR)}} = P_{D \text{ (ave)}} \cdot t_{av}$$



**Fig 17.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



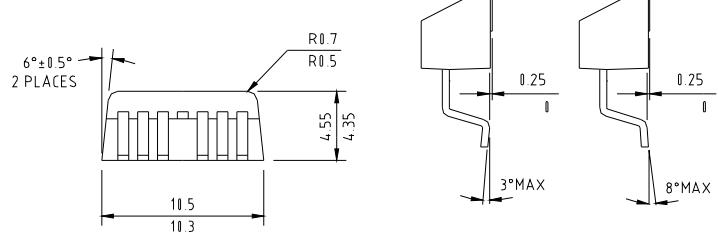
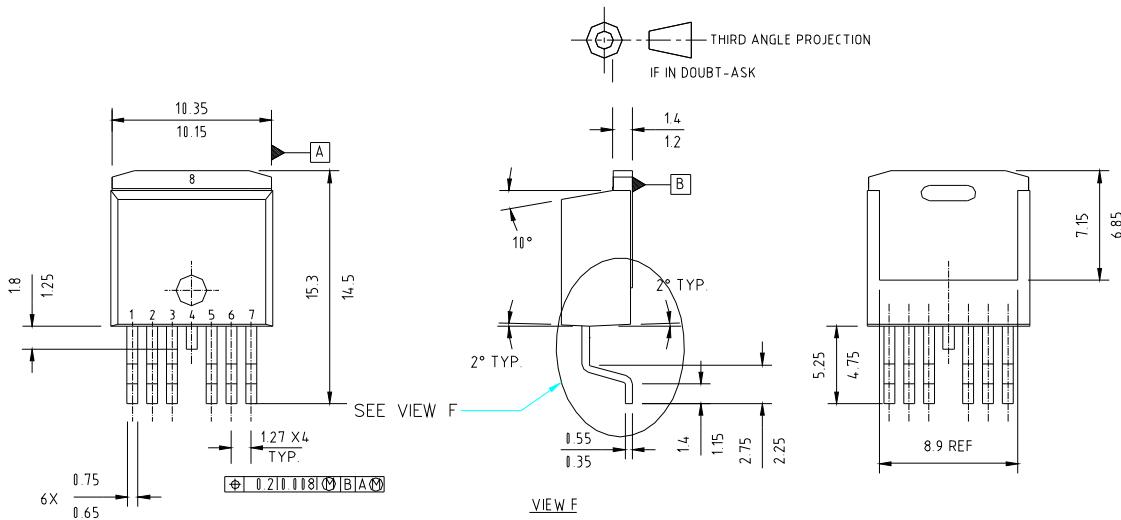
**Fig 18a.** Switching Time Test Circuit



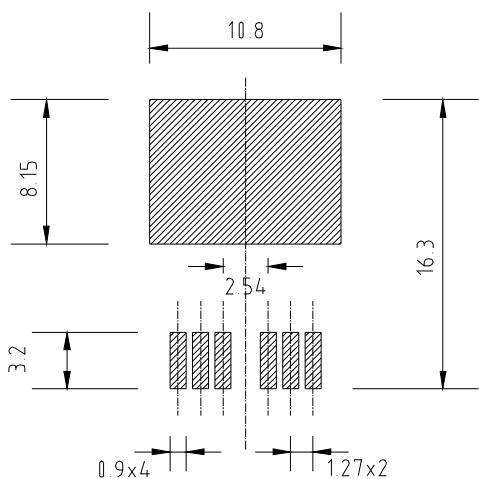
**Fig 18b.** Switching Time Waveforms

D<sup>2</sup>Pak - 7 Pin Package Outline

Dimensions are shown in millimeters (inches)



Lead Assignment	
1	- Gate
2	- Source
3	- Source
4	- Drain
5	- Source
6	- Source
7	- Source
8	- Drain

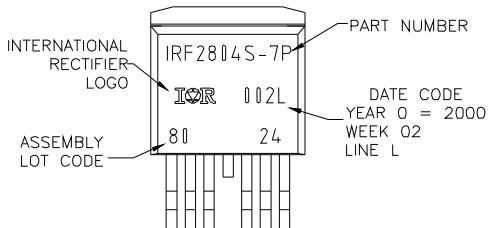
RECOMMENDED FOOTPRINT

REV	DATE	MODIFICATION
-	18/03/03	RAISED IAW ECN 3426
Rev1	07/04/03	CHANGED IAW ECN 3438
A	23/04/04	ADD LEAD ASSIGNMENT

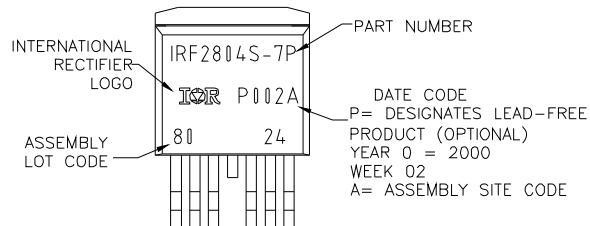
## D<sup>2</sup>Pak - 7 Pin Part Marking Information

EXAMPLE: THIS IS AN IRF2804S-7P WITH  
LOT CODE 8024  
ASSEMBLED ON WW02,2000  
IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line  
position indicates "Lead Free"



OR



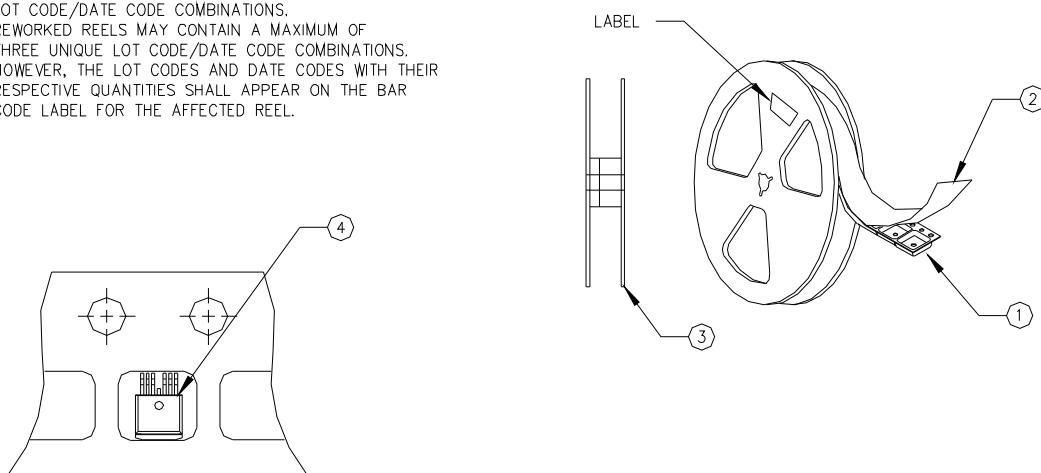
## D<sup>2</sup>Pak - 7 Pin Tape and Reel

### NOTES, TAPE & REEL, LABELLING:

1. TAPE AND REEL.
  - 1.1 REEL SIZE 13 INCH DIAMETER.
  - 1.2 EACH REEL CONTAINING 800 DEVICES.
  - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
  - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
  - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
  - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS. REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS. HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.

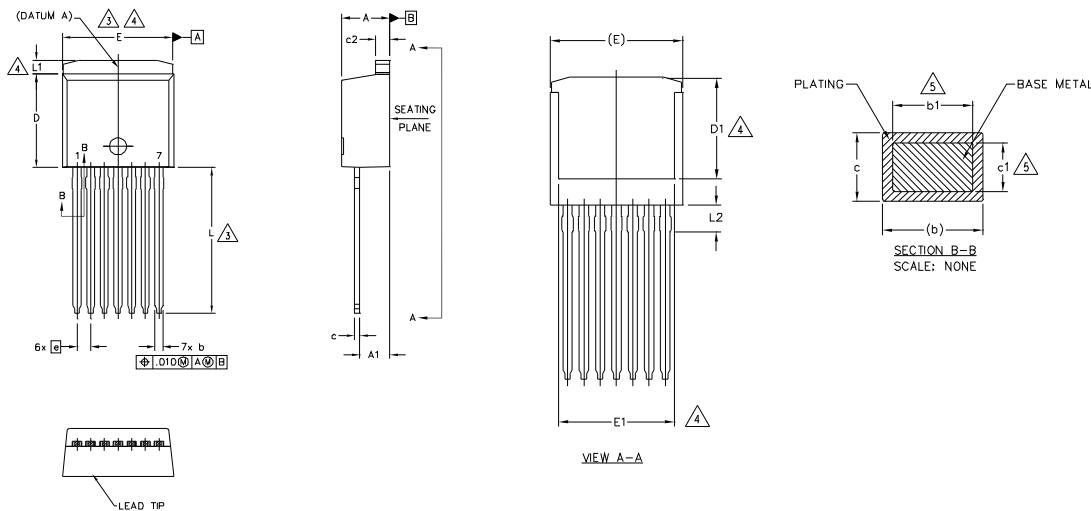
### 2. LABELLING (REEL AND SHIPPING BAG).

- 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
- 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
- 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
- 2.4 QUANTITY:
- 2.5 VENDOR CODE: IR
- 2.6 LOT CODE:
- 2.7 DATE CODE:



## TO-263CA 7 Pin Long Leads Package Outline

Dimensions are shown in millimeters (inches)



## NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994

2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D &amp; E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 &amp; E1.

5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.

6. CONTROLLING DIMENSION: INCH.

7. - OUTLINE CONFORM TO JEDEC TO-263 CA

SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.91	.020	.036		
b1	0.51	0.81	.020	.032	5	
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.51	9.65	.335	.380	3	
D1	6.86	-	.270	-	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	-	.245	-	4	
e	1.27 BSC		.050 BSC			
L	13.46	14.10	.530	.555		
L1	-	1.65	-	.065	4	
L2	-	6.35	-	.250		

LEAD ASSIGNMENTS
HEXFET

- 1.- GATE
- 2.- SOURCE
- 3.- SOURCE
- 4.- DRAIN
- 5.- SOURCE
- 6.- SOURCE
- 7.- SOURCE

International  
  
Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA

To contact International Rectifier, please visit <http://www.irf.com/photocall/>